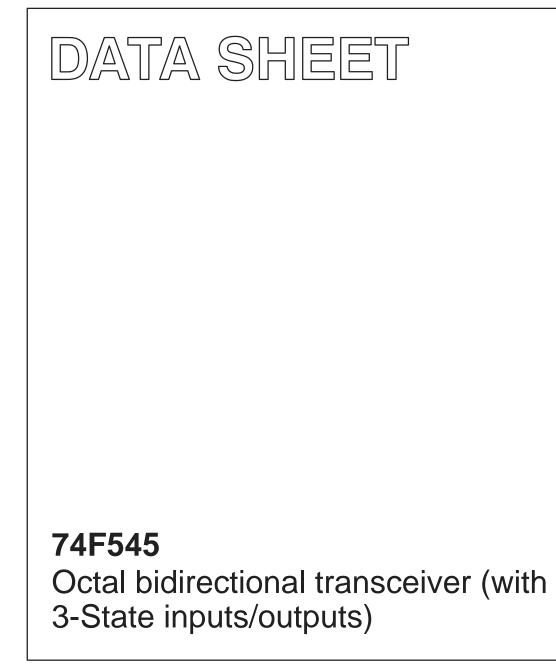
# INTEGRATED CIRCUITS



Product specification

1990 Mar 01

IC15 Data Handbook



Philips Semiconductors

74F545

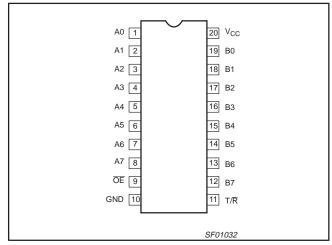
#### **FEATURES**

- High impedance NPN base inputs for reduced loading (70μA in High and Low states) output
- 8-bit bidirectional data flow reduces system package count
- 3-State inputs/outputs for interfacing with bus oriented systems
- 24mA and 64mA bus drive capability on A and B ports, respectively
- Transmit/Receive and Output Enable simplify control logic

### DESCRIPTION

The 74F545 is an 8-bit, 3-State, high speed transceiver. It provides bidirectional drive for the bus-oriented microprocessor and digital communications systems. Straight through bidirectional transceivers are featured, with 24mA bus drive capability on the A ports and 64mA bus drive capability on the B ports. One input, Transmit/Receive (T/ $\mathbb{R}$ ) determines the direction of logic signals through the bidirectional transceiver. Transmit enables data from A ports to B ports; Receive enables data from B ports to A ports. The Output Enable input disables both A and B ports by placing them in a 3-State condition. The 74F545 performs the same function as the 74F245, the only difference being package pin assignment.

#### **PIN CONFIGURATION**



TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F545	4.0ns	87mA

### **ORDERING INFORMATION**

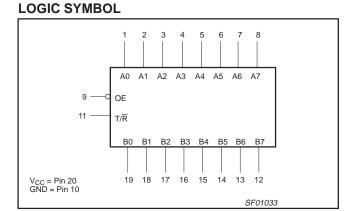
DESCRIPTION	COMMERCIAL RANGE V <sub>CC</sub> = 5V ±10%, T <sub>amb</sub> = 0°C to +70°C	PKG DWG #	
20-Pin Plastic DIP	N74F545N	SOT146-1	
20-Pin Plastic SOL	N74F545D	SOT163-1	

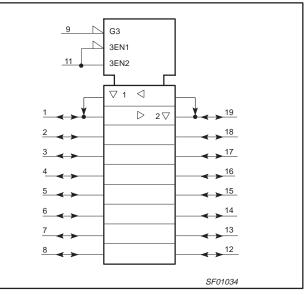
### INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
A0–A7, B0–B7	Data inputs	3.5/0.117	70μΑ/70μΑ
ŌĒ	Output Enable input (active Low)	2.0/0.067	40μΑ/40μΑ
T/R	Transmit/Receive input	2.0/0.067	40μΑ/40μΑ
A0 - A7	Port A 3-State outputs	150/40	3.0mA/24mA
B0 - B7	Port B 3-State outputs	750/107	15mA/64mA

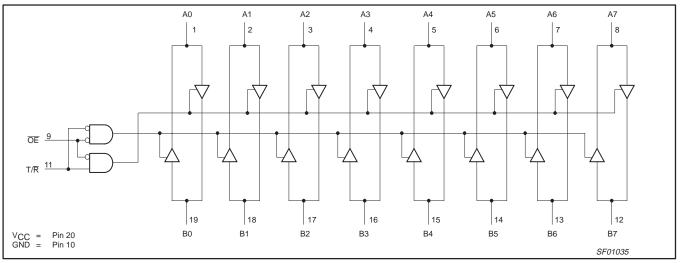
NOTE: One (1.0) FAST Unit Load is defined as: 20µA in the High state and 0.6mA in the Low state.

### 74F545





### LOGIC DIAGRAM



### **FUNCTION TABLE**

INP	JTS	OUTPUTS
OE	T/R	
L	L	Bus B data to Bus A
L	Н	Bus A data to Bus B
Н	Х	Z

H = High voltage level L = Low voltage level

X = Don't care

Z = High impedance "off" state

### LOGIC SYMBOL (IEEE/IEC)

74F545

### **ABSOLUTE MAXIMUM RATINGS**

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER		RATING	UNIT
V <sub>CC</sub>	Supply voltage		-0.5 to +7.0	V
V <sub>IN</sub>	Input voltage		-0.5 to +7.0	V
I <sub>IN</sub>	Input current	-30 to +5.0	mA	
V <sub>OUT</sub>	Voltage applied to output in High output state		-0.5 to +5.5	V
		A0–A7	48	mA
IOUT	Current applied to output in Low output state	B0–B7	128	mA
T <sub>amb</sub>	Operating free-air temperature range	-	0 to +70	°C
T <sub>stq</sub>	Storage temperature		-65 to +150	°C

### **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER		UNIT			
STWBOL					MAX	UNIT
V <sub>CC</sub>	Supply voltage		4.5	5.0	5.5	V
V <sub>IH</sub>	High-level input voltage		2.0			V
V <sub>IL</sub>	Low-level input voltage			0.8	V	
I <sub>IK</sub>	Input clamp current				-18	mA
	High lovel output ourrept	A0–A7			-3	mA
юн	High-level output current	B0–B7			-15	mA
		A0–A7			24	mA
IOL	Low-level output current	B0–B7			64	mA
T <sub>amb</sub>	Operating free-air temperature range	-	0		70	°C

74F545

### DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	DADAMETED	DADAMETED			TEST CONDITIONS <sup>1</sup>				
STMBUL	PARAMETER		TEST CONDITIONS.			MIN	TYP <sup>2</sup>	MAX	UNIT
		A0–A7		1 2mA	±10%V <sub>CC</sub>	2.4			V
	High-level output voltage	B0–B7	V <sub>CC</sub> = MIN, V <sub>IL</sub> = MAX,	I <sub>OH</sub> = -3mA	±5%V <sub>CC</sub>	2.7	3.3		V
Vон	High-level output voltage	B0B7	$V_{IH} = MIN$	I <sub>OH</sub> = -15mA	±10%V <sub>CC</sub>	2.0			V
		DU-D7		10H = -10HA	±5%V <sub>CC</sub>	2.0			V
		A0-A7			±10%V <sub>CC</sub>		0.35	0.50	V
	Low-level output voltage	AU-A7	V <sub>CC</sub> = MIN, V <sub>IL</sub> = MAX,	IOL = 2411A	±5%V <sub>CC</sub>		0.35	0.50	V
V <sub>OL</sub>	Low-level output voltage	B0–B7	$V_{IH} = MIN$	I <sub>OL</sub> = MAX	±10%V <sub>CC</sub>			0.55	V
		00-07		IOL = MAX	±5%V <sub>CC</sub>		0.42	0.55	V
V <sub>IK</sub>	Input clamp voltage		$V_{CC} = MIN, I_I = I_{IK}$				-0.73	-1.2	V
	Input current at	OE, T/R	V <sub>CC</sub>	$V_{CC} = 0.0V, V_{I} = 7.0V$				100	μΑ
lı	maximum input voltage	A0–A7, B0–B7	V <sub>CC</sub>	= 5.5V, V <sub>I</sub> = 5.5	SV .			1.0	mA
I <sub>IH</sub>	High-level input current	OE, T/R	V <sub>CC</sub>	= MAX, V <sub>I</sub> $=$ 2.7	7V			40	μΑ
IIL	Low-level input current	only	V <sub>CC</sub>	= MAX, V <sub>I</sub> $=$ 0.5	5V			-40	μA
I <sub>OZH</sub> +I <sub>IH</sub>	Off-state output current High-level voltage applied		V <sub>CC</sub>	= MAX, V <sub>I</sub> = 2.7	7V			70	μΑ
I <sub>OZL</sub> +I <sub>IL</sub>	Off-state output current Low-level voltage applied		$V_{CC} = MAX, V_I = 0.5V$					-70	μΑ
I	Short-circuit output	A0–A7	V <sub>CC</sub> = MAX		-60		-150	mA	
los	current <sup>3</sup>	B0–B7			-100		-225	μΑ	
		I <sub>CCH</sub>		T/R=An=4.5V,	OE=GND		84	100	mA
lcc	Supply current (total) <sup>4</sup>	I <sub>CCL</sub>	$V_{CC} = MAX$	OE=T/R =Bn=	GND		96	120	mA
		I <sub>CCZ</sub>		T/R=Bn=GND	, <u>OE</u> =4.5V		96	120	mA

#### NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value under the recommended operating conditions for the applicable type.

2. All typical values are at  $V_{CC} = 5V$ ,  $T_{amb} = 25^{\circ}C$ . 3. Not more than one output should be shorted at a time. For testing  $I_{OS}$ , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, IOS should be performed last.

4. Measure I<sub>CC</sub> with outputs open.

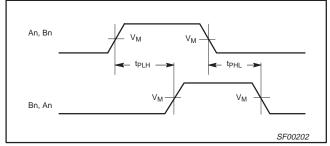
### **AC ELECTRICAL CHARACTERISTICS**

					LIMIT	S		
SYMDOL	DADAMETED	TEST	Ĭ	mb = +25°		$T_{amb} = 0^{\circ}C$		
SYMBOL	PARAMETER	CONDITIONS		<sub>CC</sub> = +5.0 0pF, R <sub>L</sub> =		V <sub>CC</sub> = +5. C <sub>1</sub> = 50pF.	$0V \pm 10\%$ R <sub>L</sub> = 500Ω	UNIT
			MIN	ТҮР	MAX	MIN	MAX	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay An to Bn, Bn to An	Waveform 1	1.5 2.5	3.5 4.5	5.5 6.5	1.5 2.5	6.5 7.0	ns ns
t <sub>PZH</sub> t <sub>PZL</sub>	Output Enable time to High or Low level	Waveform 2 Waveform 3	6.0 5.5	8.5 8.0	10.5 9.5	6.0 5.5	11.0 10.0	ns ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Output Disable time from High or Low level	Waveform 2 Waveform 3	2.5 2.0	5.0 4.5	7.0 6.5	2.5 2.0	8.0 7.5	ns ns

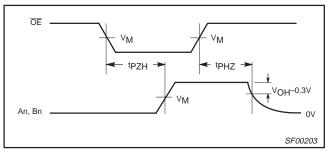
### 74F545

### AC WAVEFORMS

For all waveforms, V<sub>M</sub> = 1.5V.

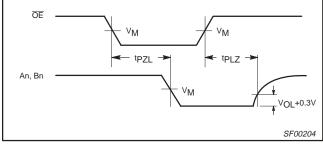




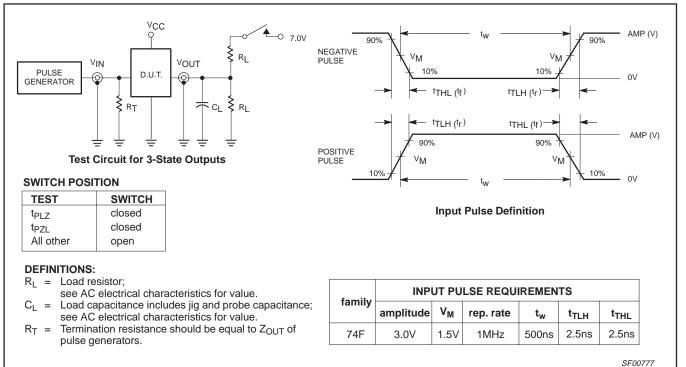


Waveform 2. 3-State Output Enable Time to High Level and Output Disable Time from High Level

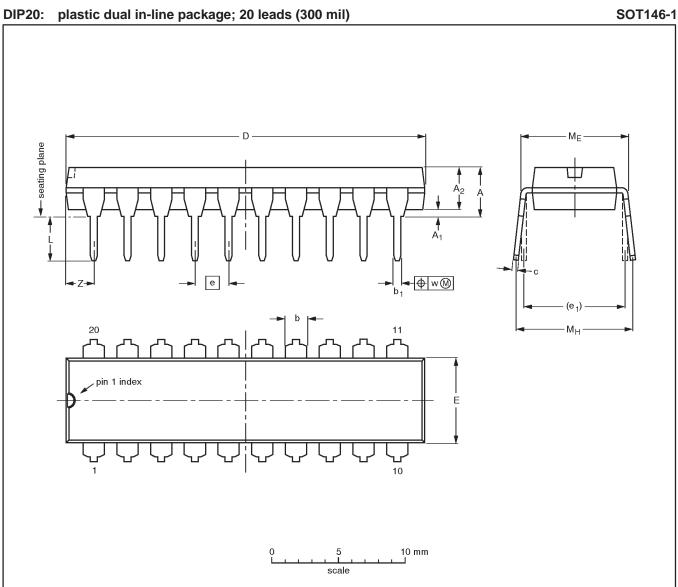
### **TEST CIRCUIT AND WAVEFORM**



Waveform 3. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level



# 74F545



### DIMENSIONS (inch dimensions are derived from the original mm dimensions)

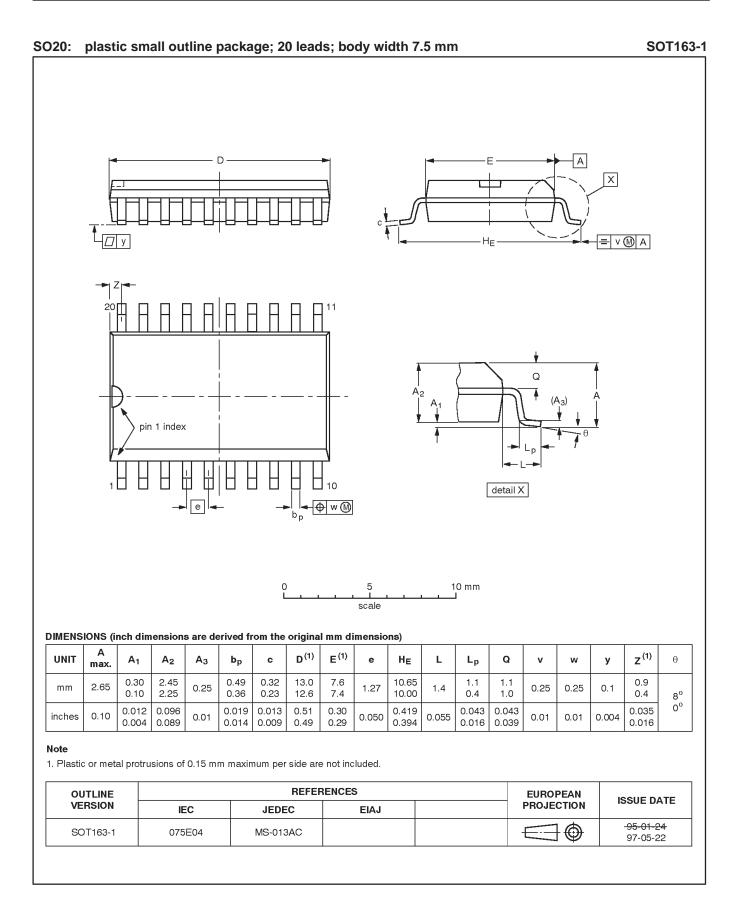
UNIT	A max.	A <sub>1</sub> min.	A <sub>2</sub> max.	b	b <sub>1</sub>	c	D <sup>(1)</sup>	E <sup>(1)</sup>	e	e <sub>1</sub>	L	M <sub>E</sub>	M <sub>H</sub>	w	Z <sup>(1)</sup> max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	0.36 0.23	26.92 26.54	6.40 6.22	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.0
inches	0.17	0.020	0.13	0.068 0.051	0.021 0.015	0.014 0.009	1.060 1.045	0.25 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.078

#### Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFEF	RENCES	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT146-1			SC603			<del>-92-11-17</del> 95-05-24

### 74F545



### Product specification

# Octal bidirectional transceiver (with 3-State inputs/outputs)

74F545

NOTES

### 74F545

#### Data sheet status

Data sheet status	Product status	Definition <sup>[1]</sup>
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

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